

**No. 35A-9 RbTiOPO<sub>4</sub>, Rubidium titanyl phosphate (RTP)***(M* = 244.32)

1a	Ferroelectricity in RbTiOPO <sub>4</sub> was suggested by Zumsteg et al. in 1976. Dielectric anomaly was confirmed by Yanovskii et al. in 1985.		76Zum 85Yan
b	phase	II	I
	state	(F)	P
	crystal system	orthorhombic	orthorhombic
	space group	Pna2 <sub>1</sub> –C <sub>2v</sub> <sup>9</sup>	Pnam–D <sub>2h</sub> <sup>16</sup>
	Θ [°C]	789(2)	93Kad 88Vor
	<i>P</i> <sub>s</sub>    [001].		85Yan
	<i>T</i> <sub>melt</sub> = 1070 K.		76Zum
	$\rho = 3.597 \cdot 10^3 \text{ kg m}^{-3}$ ; $\rho_X = 3.626 \cdot 10^3 \text{ kg m}^{-3}$ .		88Vor
	See also Table 35A-6-001 in No. 35A-6.		
	Transparent and colorless.		88Vor
2a	Sample preparation:		
	Crystallites: see		86EIB
	Simple reaction flux method: see		71Mas
	Hydrothermal method: see		76Zum
	Growth of large clear single crystals by flux method using RbH <sub>2</sub> PO <sub>4</sub> , Rb <sub>4</sub> P <sub>2</sub> O <sub>7</sub> and TiO <sub>2</sub> as starting materials: see		90Wan
	Crystal growth from tungstate and molybdate fluxes. Crystal size: 2.5 × 3 × 5 cm <sup>3</sup> : see		91Che
	Growth of single crystals from phosphate systems Rb <sub>2</sub> O–P <sub>2</sub> O <sub>5</sub> –(TiO <sub>2</sub> ) <sub>2</sub> : see		92Ose
	Crystal growth by flux method: see		93Kad
	Crystal growth by flux method, flux is Rb <sub>6</sub> P <sub>4</sub> O <sub>13</sub> : see		94Che
	Epitaxial growth of films on KTiOPO <sub>4</sub> substrates by laser ablation technique: see		94Liu
b	Crystal habit: Fig. 35A-9-001.		
3a	<i>a</i> = 12.948(2) Å, <i>b</i> = 6.4942(9) Å, <i>c</i> = 10.551(1) Å, <i>V</i> = 887.2 Å <sup>3</sup> . See also Table 35A-6-001 in No. 35A-6, Table 35B-1-006 in No. 35B-1.		93Kad
b	<i>Z</i> = 8. Crystal structure: Table 35A-9-001; see also Table 35A-6-007 in No. 35A-6, Table 35A-11-003 in No. 35A-11, Table 35A-21-001 in No. 35A-21.		93Kad
5a	Dielectric constant: Table 35A-9-002; Fig. 35A-9-002, Fig. 35A-9-003, Fig. 35A-9-004, Fig. 35A-9-005, Fig. 35A-9-006; see also Fig. 35A-6-013 in No. 35A-6, and		88Vor, 85Yan
7a	Piezoelectricity: Table 35A-9-002.		
8a	Elastic compliances and stiffnesses: Table 35A-9-002. See also Table 35A-6-012 in No. 35A-6.		
9a	Refractive index: Table 35A-9-003; Fig. 35A-9-007; see also Table 35A-6-013 in No. 35A-6. Electrooptical coefficients at 20 °C: <i>r</i> <sub>13</sub> = 9.7, <i>r</i> <sub>23</sub> = 10.8, <i>r</i> <sub>33</sub> = 22.5, <i>r</i> <sub>51</sub> = –7.6, <i>r</i> <sub>42</sub> = 14.9 [· 10 <sup>–12</sup> m V <sup>–1</sup> ]. Optical transmission: Fig. 35A-9-008; see also Fig. 35A-6-037 in No. 35A-6.		90Wan

### 35 $\text{KTiOPO}_4$ (KTP) family

<hr/>	
b	Electrooptic effect: Table 35A-6-018 in No. 35A-6.
e	Nonlinear optical properties: Fig. 35A-9-009. See also Table 35A-6-018 in No. 35A-6, Table 35B-1-006 in No. 35B-1.
<hr/>	
10a	Raman scattering: Table 35A-9-004, Table 35A-9-005; Fig. 35A-9-010. See also Table 35A-6-023; Fig. 35A-6-069 in No. 35A-6.
<hr/>	
11	Electrical conductivity: Fig. 35A-9-011, Fig. 35A-9-012, Fig. 35A-9-013. See also Fig. 35A-6-084 in No. 35A-6. Luminescence: see Table 35A-6-025 in No. 35A-6.
<hr/>	
13a	$^{31}\text{P}$ NMR: see Fig. 35B-1-017 in No. 35B-1.
<hr/>	
15a	Domain pattern observation by chemical etching and by a scanning electron microscope: see 87Vor
<hr/>	
16	Observation of the dislocation etch pits: see 87Vor
<hr/>	